

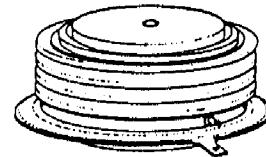
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HIGH SPEED
Silicon
Controlled Rectifier
1200 Volts, 650 A RMS

C397/C398

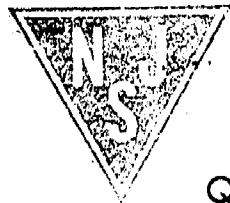


MAXIMUM ALLOWABLE RATINGS

TYPES	REPETITIVE PEAK OFF-STATE VOLTAGE, V_{DRM}^1 $T_J = -40^\circ\text{C}$ to $+125^\circ\text{C}$	REPETITIVE PEAK REVERSE VOLTAGE, V_{RRM}^1 $T_J = -40^\circ\text{C}$ to $+125^\circ\text{C}$	NON-REPETITIVE PEAK REVERSE VOLTAGE, V_{RSM}^1 $T_J = 125^\circ\text{C}$
C397/C398E	500 Volts	500 Volts	600 Volts
C397/C398M	600	600	720
C397/C398S	700	700	840
C397/C398N	800	800	960
C397/C398T	900	900	1080
C397/C398P	1000	1000	1200
C397/C398PA	1100	1100	1300
C397/C398PB	1200	1200	1400

¹ Half sinewave waveform, 10 ms max. pulse width.

Peak One Cycle Surge (Non-Repetitive) On-State Current, I_{TSM}	7500 Amperes
I^2t (for fusing) for times ≥ 1.5 milliseconds	95,000 (RMS Ampere) ² Seconds
I^2t (for fusing) for times ≥ 8.3 milliseconds	230,000 (RMS Ampere) ² Seconds
Critical Rate-of-Rise of On-State Current, Non-Repetitive	800 A/ μ s †
Critical Rate-of-Rise of On-State Current, Repetitive	500 A/ μ s †
Average Gate Power Dissipation, $P_G(\Delta V)$	2 Watts
Storage Temperature, T_{stg}	-40°C to $+150^\circ\text{C}$
Operating Temperature, T_J	-40°C to $+125^\circ\text{C}$
Mounting Force Required	2000 Lb. $\pm 10\%$ 8.9 KN $\pm 10\%$



Quality Semi-Conductors

CHARACTERISTICS

TEST	SYMBOL	MIN.	TYP.	MAX.	UNITS	TEST CONDITION
Repetitive Peak Reverse and Off-State Current	I _{IRRM} and I _{IDRM}	--	5	20	mA	T _J = +25°C V = V _{IDRM} = V _{RRM}
Repetitive Peak Reverse and Off-State Current	I _{IRRM} and I _{IDRM}	--	20	45	mA	T _J = 125°C V = V _{IDRM} = V _{RRM}
Thermal Resistance	R _{θJC}	--	.05	.06	°C/Watt	Junction-to-Case (DC) (Double-Side Cooled)
Critical Rate-of-Rise of Off-State Voltage (Higher values may cause device switching)	dv/dt	200	500	--	V/μsec	T _J = 125°C, Gate Open, V _{IDRM} = Rated, Linear or Exponential Rising Waveform. Exponential dv/dt = $\frac{V_{DRM}}{\tau}$ (.632)
Higher minimum dv/dt selections available -- consult factory.						
DC Gate Trigger Current	I _{GT}	--	50	150	mAdc	T _C = +25°C, V _D = 6 Vdc, R _L = 3 Ohms
		--	75	300		T _C = -40°C, V _D = 6 Vdc, R _L = 3 Ohms
		--	15	125		T _C = +125°C, V _D = 6 Vdc, R _L = 3 Ohms
DC Gate Trigger Voltage	V _{GT}	--	3	5	Vdc	T _C = -40°C to 25°C, V _D = 6 Vdc, R _L = 3 Ohms
		--	1.25	3.0		T _C = 25°C to +125°C, V _D = 6 Vdc, R _L = 3 Ohms
		0.15	--	--		T _C = 125°C, V _{IDRM} , R _L = 1000 Ohms
Peak On-State Voltage	V _{TM}	--	2.7	3.0	Volts	T _C = +25°C, I _{TM} = 3000 Amps Peak, Duty Cycle ≤ .01%. Pulse Width = 1 ms.
Turn-On Delay Time	t _d	--	0.5	--	μsec	T _C = +25°C, I _{TM} = 50 Adc, V _{IDRM} , Gate Supply: 20 volt open circuit, 20 ohms, 0.1 μsec max. rise time, ††, †††
Conventional Circuit Commutated Turn-Off Time (with Reverse Voltage) C398 C397	t _q	--	20	†	μsec	(1) T _C = +125°C (2) I _{TM} = 500 Amps. (3) V _R = 50 Volts Min. (4) V _{IDRM} (Reapplied) (5) Rate-of-rise of reapplied off-state voltage = 20 V/μsec (linear) (6) Commutation di/dt = 25 Amps/μsec (7) Repetition rate = 1 pps. (8) Gate bias during turn-off interval = 0 volts, 100 ohms
		--	35	†		(1) T _C = +125°C (2) I _{TM} = 500 Amps. (3) V _R = 50 Volts Min. (4) V _{IDRM} (Reapplied) (5) Rate-of-rise of reapplied off-state voltage = 200 V/μsec (linear) (6) Commutation di/dt = 25 Amps/μsec (7) Repetition rate = 1 pps. (8) Gate bias during turn-off interval = 0 volts, 100 ohms
		--	30	40		(1) T _C = +125°C (2) I _{TM} = 500 Amps. (3) V _R = 50 Volts Min. (4) V _{IDRM} (Reapplied) (5) Rate-of-rise of reapplied off-state voltage = 200 V/μsec (linear) (6) Commutation di/dt = 25 Amps/μsec (7) Repetition rate = 1 pps. (8) Gate bias during turn-off interval = 0 volts, 100 ohms
		--	45	60		(1) T _C = +125°C (2) I _{TM} = 500 Amps. (3) V _R = 50 Volts Min. (4) V _{IDRM} (Reapplied) (5) Rate-of-rise of reapplied off-state voltage = 200 V/μsec (linear) (6) Commutation di/dt = 25 Amps/μsec (7) Repetition rate = 1 pps. (8) Gate bias during turn-off interval = 0 volts, 100 ohms
		--	40	†		(1) T _C = +125°C (2) I _{TM} = 500 Amps (3) V _R = 1 Volt (4) V _{IDRM} (Reapplied) (5) Rate-of-rise of reapplied off-state voltage = 200 V/μsec (linear) (6) Commutation di/dt = 25 Amps/μsec (7) Repetition rate = 1 pps. (8) Gate bias during turn-off interval = 0 volts, 100 ohms
		--	60	†		(1) T _C = +125°C (2) I _{TM} = 500 Amps (3) V _R = 1 Volt (4) V _{IDRM} (Reapplied) (5) Rate-of-rise of reapplied off-state voltage = 200 V/μsec (linear) (6) Commutation di/dt = 25 Amps/μsec (7) Repetition rate = 1 pps. (8) Gate bias during turn-off interval = 0 volts, 100 ohms
Conventional Circuit Commutated Turn-Off Time (with Feedback Diode) C398 C397	t _{q(diode)}	--			μsec	(1) T _C = +125°C (2) I _{TM} = 500 Amps (3) V _R = 1 Volt (4) V _{IDRM} (Reapplied) (5) Rate-of-rise of reapplied off-state voltage = 200 V/μsec (linear) (6) Commutation di/dt = 25 Amps/μsec (7) Repetition rate = 1 pps. (8) Gate bias during turn-off interval = 0 volts, 100 ohms